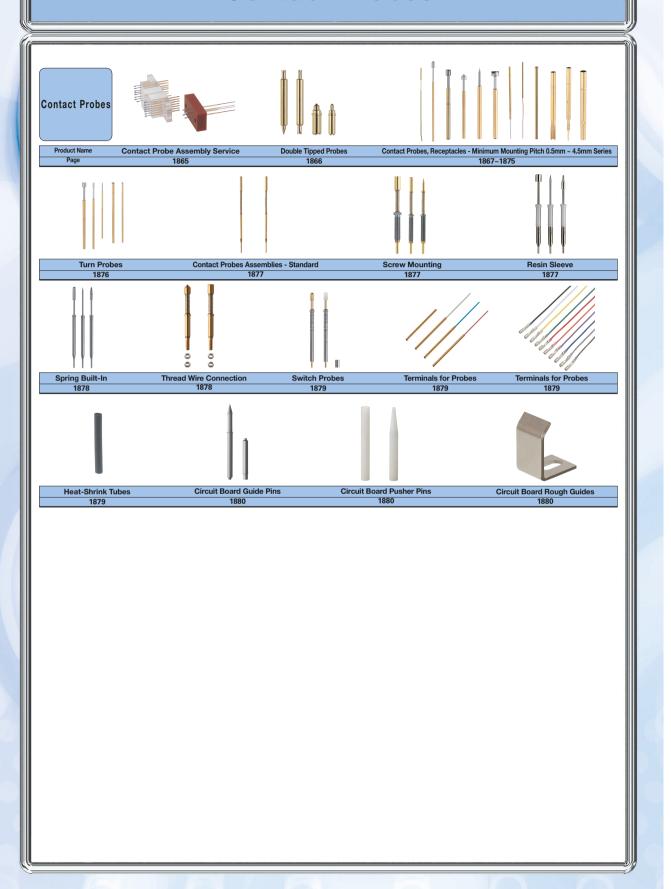
# **Contact Probes**



## **Contact Probes**

### Overview

#### Overview

Contact Probes can be used in connection tests of all electronic circuits.

Press-fit appropriate receptacles in the mating holes drilled in a bakelite or other plastic plate. If the mating holes are loose, use appropriate adhesives (Loctite, etc.) to fill the gap. After press fitting, wire the receptacles. If wires need to be soldered, do not solder past the stopper in the receptacle. After wiring, insert Contact Probes. Pressing plungers too hard may cause damage to the tip or internal components of Contact Probes and result in performance

It is recommended to make several tests under operating environment before actual use.

#### Major Types and Typical Uses

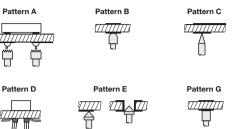
5.00

17.0

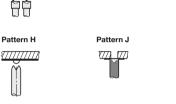
Type	Typical Uses		
Contact Probes	Suitable for extensive use in testing printed circuit boards, mounted circuit boards, semiconductors/in-circuit, harnesses, etc.		
Double Tipped Probes	Suitable for narrow pitch mounting since receptacle is not needed.		
Turn Probes	The plunger rotates with stroke movements to destroy flux and oxide film. Proven successful in open/short circuit tests of printed circuit boards.		
Integrated Probes	Contact Probe constructed in end-to-end one continuous piece. Permits stable electrical conduction regardless of the stroke length.		

Selection Table Printed in Black: Products available on our we							
Mounting Ditch			Spring Pressure Part Number			D	
Туре	, ,	ruii Stroke	(2/3 Stroke)	Probe	Receptacles	Page	
	0.3	1.3	6	RNP20	-		
		0.8	15	RNP30	-		
	0.5	1.0	15	RNP38	-	_	
ouble		0.98	25	RNP38N	-	_	
pped		1.0	25	RNP50	-	_	
robes	0.8	0.98	30	RNP57	-	_	
ODCO	0.0	1.0	30	RNP64	-	_	
		0.5	25	RNP60ST	-	-	
	1.0	0.98	35	RNP85	-		
		0.5	30	RNP80ST	-		
	0.50		16	NP26	NR26	-	
	0.60	2.0	22	NP31	NR31/NR31S		
			23	NP31HD		-	
	0.80		35	NP38	NR38/NR38S	-	
	0.90		50	NP20	NR20K	-	
	1.00		50	NP58	NR58	-	
			45	NP30	NR30K/NR30SH-B		
		2.5	46	NP30HD		-	
	1.07	2.5	50	NP72	NR72K		
	1.27		100	NP72HD		-	
		4.3	50	NP68S3SF	NR68/NR68S		
		6.0	90 150	NP68S3 NP76	NR76	-	
		6.0	50	NP68SF	NH/6	-	
	1.40	4.3			NR68/NR68S		
			90 50	NP68 NP88		-	
	1.50	2.5	100	NP88HD	NR88		
			50	NP45S3SF	NR45S	-	
		3.0	100	NP45S3			
	1.70		50	NP45SF	NR45/NR45T	_	
ontact robe	1.70	5.0	100	NP45			
obe		5.0	150	NP45HD			
			50	NP120		-	
	2.00	6.5	100	NP120HD	NR120/NR120T		
			100	TP604		1	
		4.0	110	NP604	NR604		
		4.0	160	NP604HD			
	2.54		50	NP60SF		_	
		6.4	100	NP60S	NR60		
			150	NP60/NP60H			
			170	NP60HD			
			50	NP84SF			
	3.00	3.00		NP84	NR84		
-		0	200	NP84HD	1		
				50	NP90SF		1
	3.50 4.50	3.50		150	NP90	NR90	
			6.4	250	NP90HD		
			6.4	100	NP89SF		1
		0	275	NP89S	NR89		
				450	NP89		
ceptacles ceptacle-less	1.90	7.0	170	NP16	-		
	1.27	4.5	50	TNP72	NR72	<del>                                     </del>	
ırn	1.90	5.5	140	TNP10	NR10	1	
robe	2.54	6.4	165	TNP60	NR60	1	
	0.80			GNP6	-	-	
	1.00	3.4	80	GNP8	-	1	
	1.50	4.0	95	GNP12	-	1	
tegrated obe	3.00	4.5	105	FNP10	-	1	
	5.00	4.0	100	FNP13	-	1	
			100	FNP22SF	-	1	
	obe	3.00	7.0	150	FNP22	-	1
	0.00	8.0	180	FNPS22	-		
	4.00	8.0	200	FNPS35	-	1	
			220	FNP40SF	-	1	

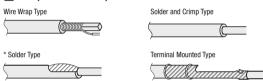
#### **■**Contact Probe Tip Shapes and Patterns



Pattern N {////////



#### Receptacle End Shapes



\*Solder Types (C Type and NR68S) are slightly bulged on the soldered ends due to the manufacturing method. That will present no problem as long as the probe is pushed in firmly, but the O.D. adjustments are allowed as needed.

#### General Environmental Conditions

• Operating Temperature: 10 ~ 40°C, Humidity: 30% or Less

• Operating Atmosphere: Free of dust, corrosive gases and oil components etc., where the contact

#### Stroke Conditions

Apply load in the axial direction only. Do not apply lateral load.
 Stroking over the specified stroke (2/3 of full stroke) will significantly decrease the lifetime of the

• Stroking over 60 times per min (constant velocity) may decrease the lifetime of the Contact

Current Application Conditions

Apply current only after contact is made at a specified position in a static state.

-Applying current while stroking, with irregular strokes, or in open state where the contact subject is not contacted will severely decrease the lifetime of Contact Probes.
- May not meet allowable current shown in the catalog due to contact probe's deterioration. Consider actual applications carefully in the designing stage

#### Voltage Application Conditions

Apply current only after contact is made at a specified position in a static state.
 Do not energize probes in open (not in contact) state. Discharge before contacting will result in

• When applying high voltage to a contact probe, be sure to satisfy Current Application Conditions and Voltage Application Conditions, and be careful of instantaneous large current including discharge.

#### Allowable Current

• Allowable current provided in the catalog is the maximum continuous current for 1 min under the conditions as shown above (Normal environment, stroke, current and voltage applied).

#### Resistance

Resistance value provided in the catalog is the representative value as shown above (Normal environment, stroke, current and voltage applied), when 10mA current flows where pure silver control to vity read for the order. contacts are used for the measurement

Large current may cause deterioration of contact and inner parts, resulting in resistance value increase.

Stroke cycle repetition may cause deterioration of contacts and inner parts, resulting in resistance increase.

# Replacement Cycle (Reference) Replacement cycle provided in the catalog is the representative value as shown above (Normal environment, stroke, current and voltage applied), when 10mA current flows. Replacement cycle can vary depending on operating environment and conditions including resistance increase and spring pressure decrease. Replace Contact Probes considering actual applications.

### Spring Pressure

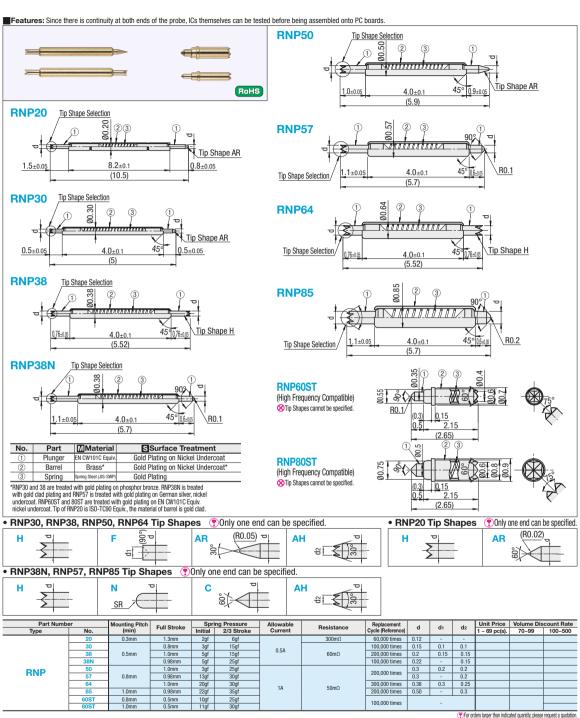
· Spring pressure decreases if temperature of contact probe is 80°C or more

• Spring pressure may decrease due to heat generation of a contact probe at larger current.

## Mounting Hole for Press-Fitting Dimension (Reference)

• The values provided are for reference. Appropriate dimensions vary depending on material and thickness of resin plate. Please take the dimensions of receptacle press fit part as a guide for your design.

# **Double Tipped Probes (For IC Test Socket)**

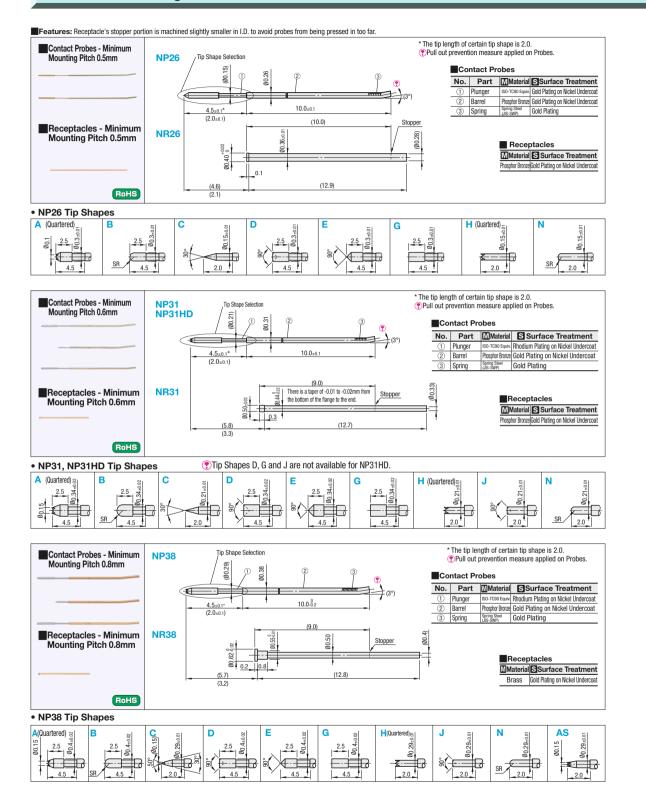


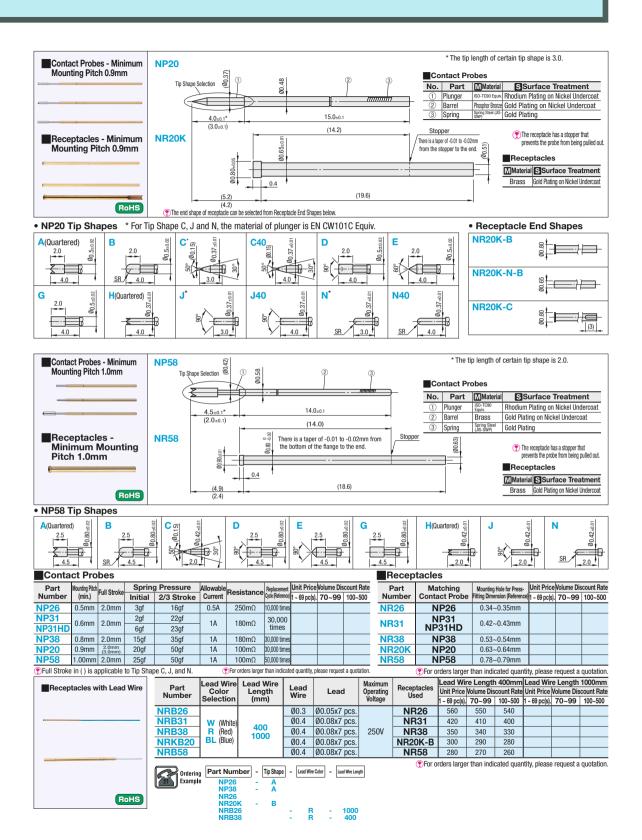


Printed Circuit Board

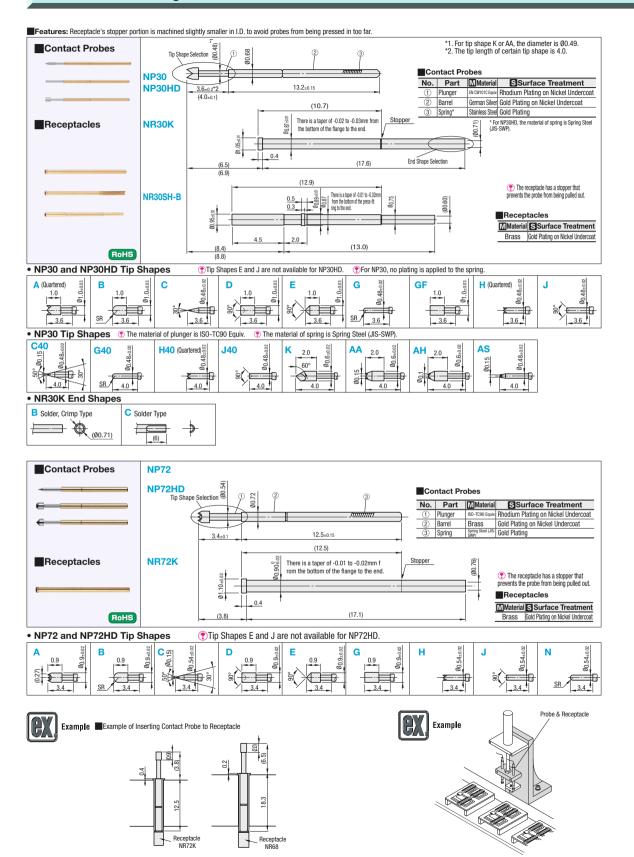
Reference Barrel Hole Dia.						
Part Number	Barrel O.D.	Reference Barrel Hole Dia.				
RNP20	0.20	0.22				
RNP30	0.30	0.32				
RNP38	0.38	0.40				
RNP38N	0.38	0.40				
RNP50	0.50	0.52				
RNP57	0.57	0.59				
RNP64	0.64	0.66				
RNP85	0.85	0.87				
RNP60ST	0.6	0.65				
RNP80ST	0.8	0.85				

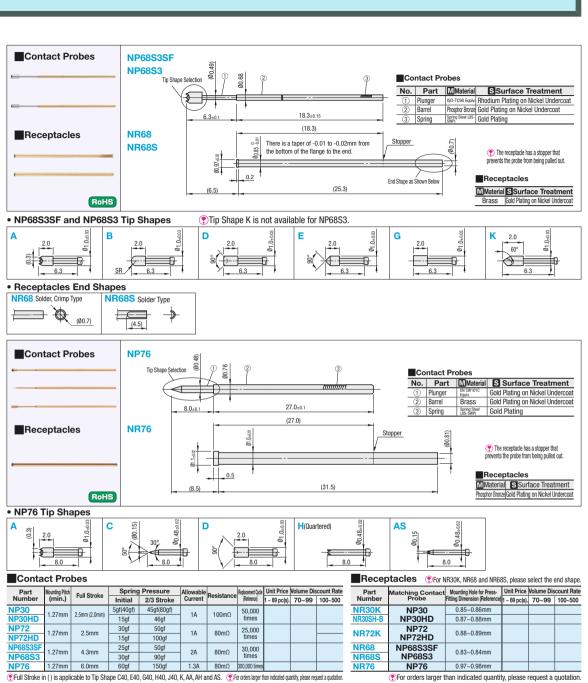
Minimum Mounting Pitch 0.5mm / 0.6mm / 0.8mm / 0.9mm / 1.0mm Series

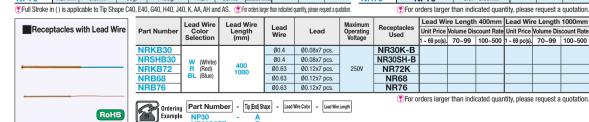




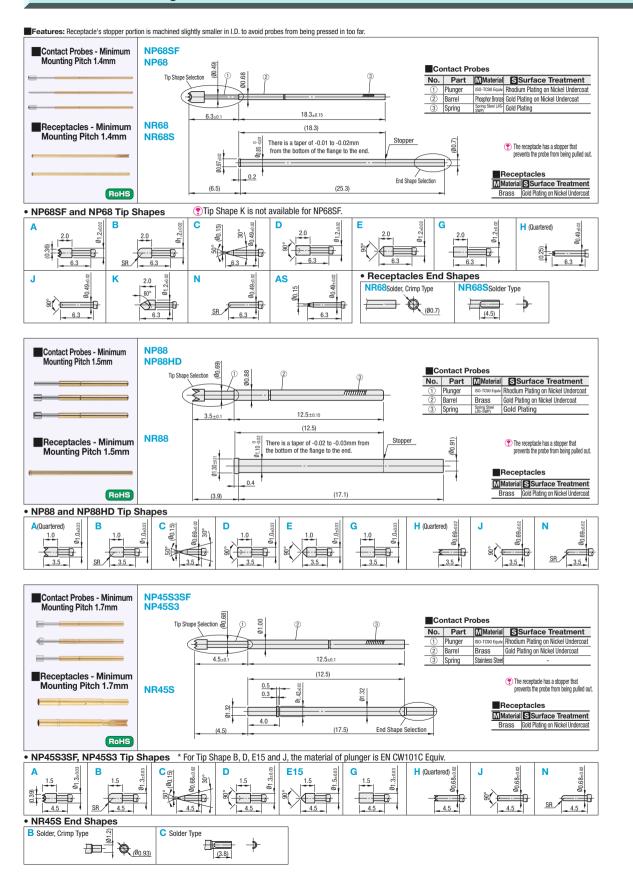
## **Minimum Mounting Pitch 1.27mm Series**

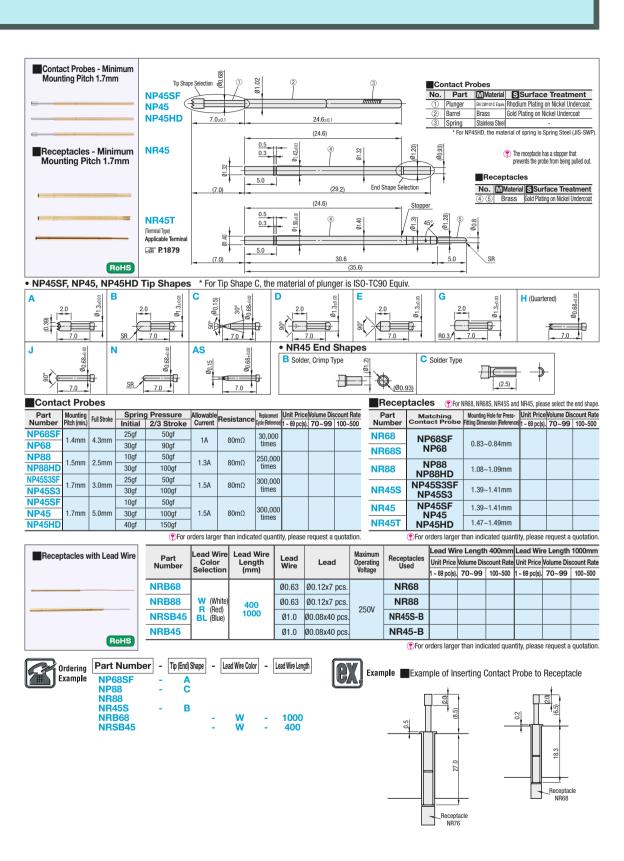




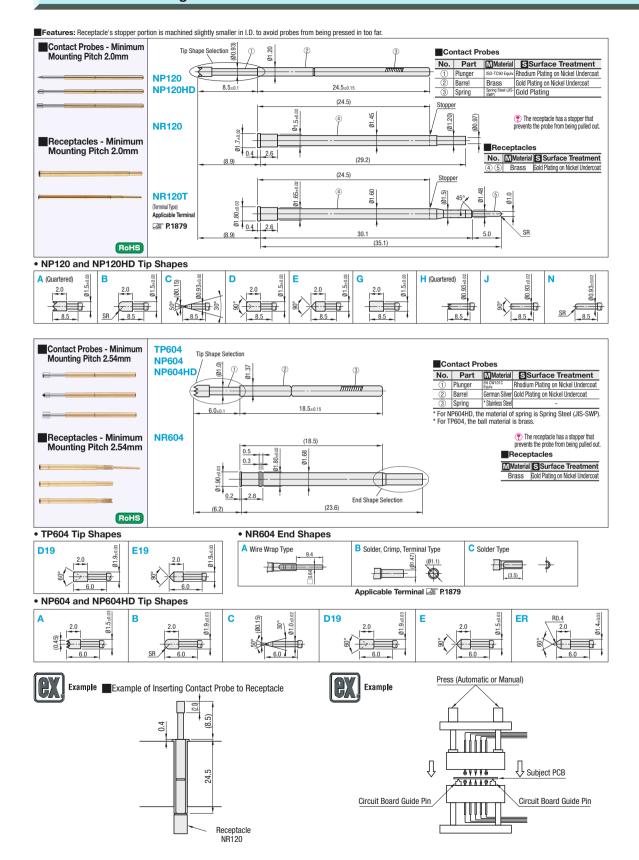


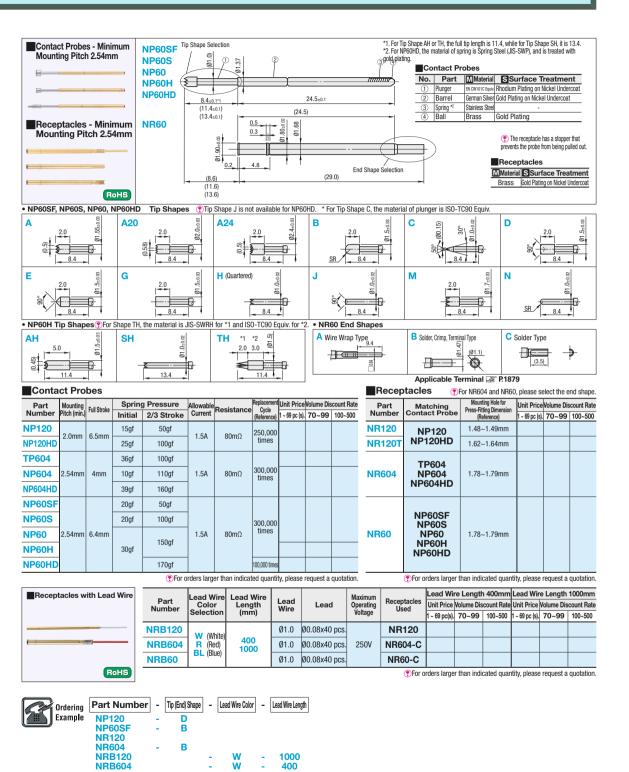
Minimum Mounting Pitch 1.4mm / 1.5mm / 1.7mm Series



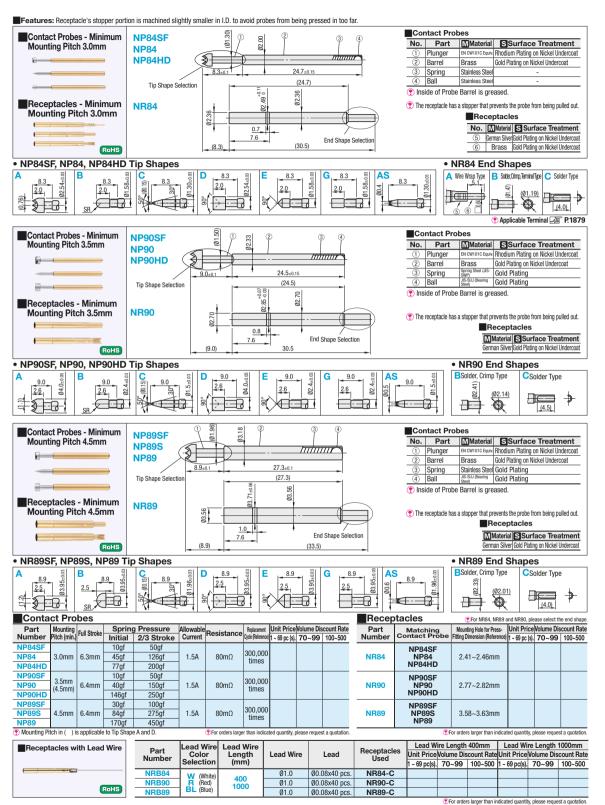


## Minimum Mounting Pitch 2.0mm / 2.54mm Series

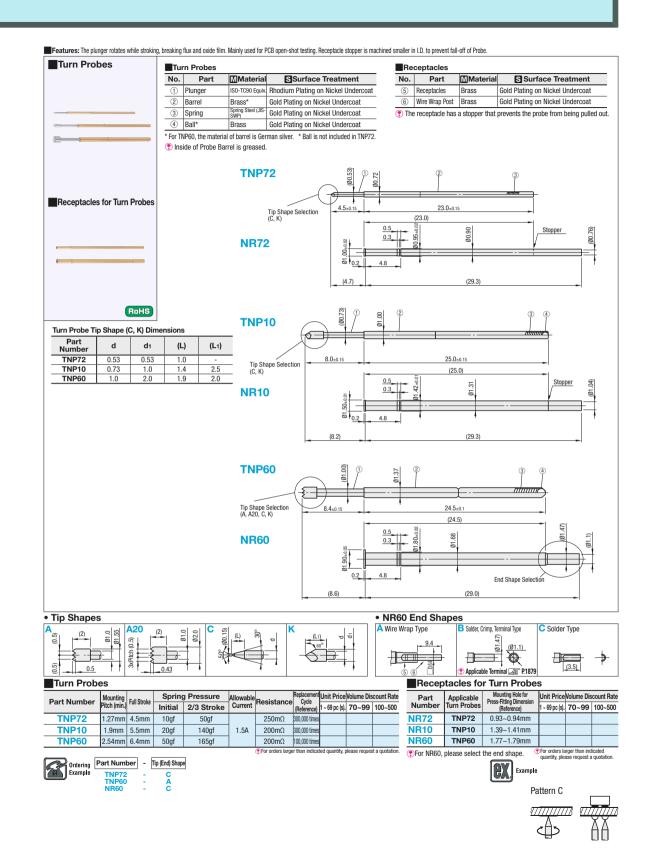




Minimum Mounting Pitch 3.0mm / 3.5mm / 4.5mm Series



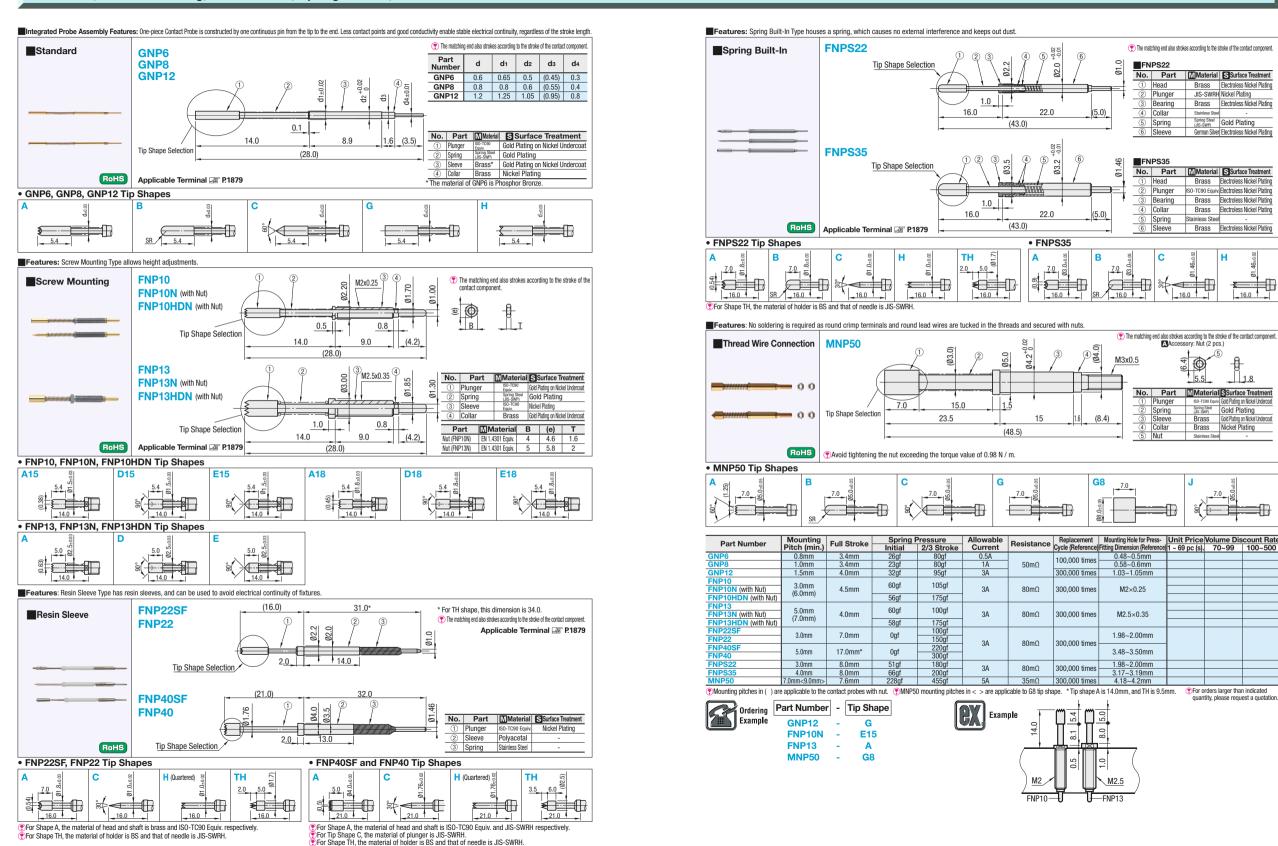
## **Turn Probes**





## **Contact Probes Assemblies**

Standard, Screw Mounting, Resin Sleeve, Spring Built-In, Thread Wire Connection



Brass Electroless Nickel Plating

Brass Electroless Nickel Plating

ISO-TC90 Equiv. Electroless Nickel Plating

Brass Electroless Nickel Plating

Brass Electroless Nickel Plating

Brass Electroless Nickel Platino

Spring Steel (JRS-SWP) Gold Plating

Brass Gold Plating on Nickel Undercoat

For orders larger than indicated

Plunger JIS-SWRH Nickel Plating

Stainless Stee

Plunger

Head

## Switch Probes / Terminals for Probes / Heat-Shrink Tubes

# Circuit Board Guide Pins / Circuit Board Pusher Pins / Circuit Board Rough Guides

